

[About IEEE](#) | [IEEE Memberships](#) | [Products and Services](#) | [Conferences](#) | [IEEE Organizations](#) | [News](#) | [Home](#)

Search

[Help](#) [FAQ](#) [Terms](#) [Technical Update](#)

Welcome to IEEE Xplore

- ☐ Home
- ☐ Log-out

Tables of Contents

- ☐ Journals & Magazines
- ☐ Conference Proceedings
- ☐ Standards

Search

- ☐ By Author
- ☐ Basic
- ☐ Advanced

Member Services

- ☐ Join IEEE
- ☐ Establish IEEE Web Account

Print Format

Your search matched 5 of 658548 documents.
Results are shown 15 to a page, sorted by publication year in descending order.

Results:

Journal or Magazine = JNL Conference = CNF Standard = STD

1 OO-VHDL. Object-oriented extensions to VHDL*Swamy, S.; Molin, A.; Covnot, B.*

Computer, Volume: 28 Issue: 10, Oct. 1995

Page(s): 18 -26

[\[Abstract\]](#) [\[PDF Full-Text\]](#) JNL

2 Control systems design-trends in industry*Swamy, S.*

Decision and Control, 1995., Proceedings of the 34th IEEE Conference on, V 1995

Page(s): 279 -284 vol.1

[\[Abstract\]](#) [\[PDF Full-Text\]](#) CNF

3 Hi-PASS: a computer-aided synthesis system for maximally parallel signal processing ASICs*Duncan, P.; Swamy, S.; Sprouse, S.; Potasz, D.; Jain, R.; Gafter, N.; Camm Wong, Y.; Gass, W.*

Acoustics, Speech, and Signal Processing, 1992. ICASSP-92., 1992 IEEE International Conference on, Volume: 5, 1992

Page(s): 605 -608 vol.5

[\[Abstract\]](#) [\[PDF Full-Text\]](#) CNF

4 High-performance BiCMOS 100 K-gate array*Gallia, J.D.; Yee, A.-L.; Chau, K.K.; Wang, I.-F.; Davis, H.; Swamy, S.; Ngu Ruparel, K.N.; Moore, K.; Chae, B.; Lemonds, C.E., Jr.; Eyres, P.; Yoshino, T. A.H.*

Solid-State Circuits, IEEE Journal of, Volume: 25 Issue: 1, Feb. 1990

Page(s): 142 -149

[\[Abstract\]](#) [\[PDF Full-Text\]](#) JNL

5 A 100 K gate sub-micron BiCMOS gate array*Gallia, J.; Yee, A.; Wang, I.; Chau, K.; Davis, H.; Swamy, S.; Sridhar, T.; Ngu Ruparel, K.; Moore, K.; Lemonds, C.; Chae, B.; Eyres, P.; Yoshino, T.; Pozad Rine, R.; Shah, A.*

Custom Integrated Circuits Conference, 1989., Proceedings of the IEEE 1989

Page(s): 8.6/1 -8.6/4